

ICS 77.040.99

CCS H 26



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 31351-2014

**Nondestructive test method for micropipe density of polished
monocrystalline silicon carbide wafers**

碳化硅单晶抛光片微管密度无损检测方法

(English Translation)

Issued on: December 31, 2014

Implemented on: September 1, 2015

Issued by: Standardization Administration of China

Table of Contents

What this standard covers	1
Document data	2

What this standard covers

This Standard specifies the NDT methods 4H and 6H crystal silicon carbide single crystal polished crystal emblem tube density. This Standard applies to 4H and 6H crystal silicon carbide single crystal polished microtubule density measured by the radial di

Document data

International classification (ICS): 77.040.99.

Chinese classification (CCS): H26.

Estimated length of the Chinese original: 7,730 words.